

20V N-Channel Enhancement Mode MOSFET

Description

The AP100N02D uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 20V$ $I_D = 100A$

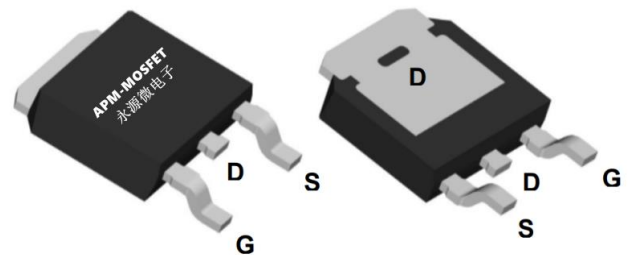
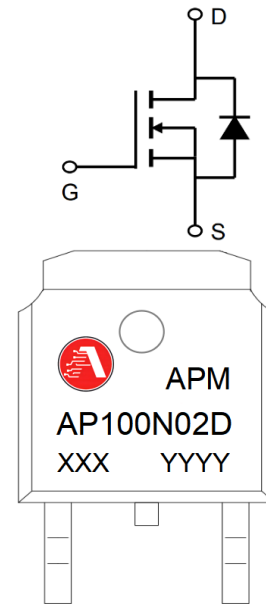
$R_{DS(ON)} < 3.5m\Omega @ V_{GS}=4.5V$ (Type: **2.8m Ω**)

Application

Battery protection

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP100N02D	TO252-3L	AP100N02D XXX YYYYY	2500

Absolute Maximum Ratings ($T_C=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Max.	Units
V_{DS}	Drain-Source Voltage	20	V
V_{GS}	Gate-Source Voltage	± 12	V
$I_D @ T_C=25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	100	A
$I_D @ T_C=100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	59	A
IDM	Pulsed Drain Current ^{note1}	360	A
EAS	Single Pulsed Avalanche Energy ^{note2}	110	mJ
P_D	Power Dissipation	81	W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.85	$^\circ C/W$
TJ, TSTG	Operating and Storage Temperature Range	-55 to +150	$^\circ C$



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Electrical Characteristics ($T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	20	22	-	V
IDSS	Zero Gate Voltage Drain Current	$V_{DS}=20V, V_{GS}=0V$	-	-	1	μA
IGSS	Gate to Body Leakage Current	$V_{GS}=\pm 12V, V_{DS}=0V$	-	-	± 100	nA
VGS(th)	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	0.5	0.68	1.0	V
RDS(on)	Static Drain-Source On-Resistance note3	$V_{GS}=4.5V, I_D=30A$	-	2.8	3.5	m Ω
		$V_{GS}=2.5V, I_D=20A$	-	4	6	
C _{iss}	Input Capacitance	$V_{DS}=10V, V_{GS}=0V, f=1.0MHz$	-	3200	-	pF
C _{oss}	Output Capacitance		-	460	-	pF
C _{rss}	Reverse Transfer Capacitance		-	445	-	pF
Q _g	Total Gate Charge	$V_{DS}=10V, I_D=30A, V_{GS}=4.5V$	-	48	-	nC
Q _{gs}	Gate-Source Charge		-	3.6	-	nC
Q _{gd}	Gate-Drain("Miller") Charge		-	19	-	nC
td(on)	Turn-On Delay Time	$V_{DS}=10V, I_D=30A, R_G=1.8\Omega, V_{GS}=4.5V$	-	9.7	-	ns
t _r	Turn-On Rise Time		-	37	-	ns
td(off)	Turn-Off Delay Time		-	63	-	ns
t _f	Turn-Off Fall Time		-	52	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	90	A
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	360	A
VSD	Drain to Source Diode Forward Voltage	$V_{GS}=0V, I_{SD}=30A, T_J=25^\circ\text{C}$	-	-	1.2	V
t _{rr}	Reverse Recovery Time	$T_J=25^\circ\text{C}, I_F=30A, di/dt=100A/\mu s$	-	23	-	ns
Q _{rr}	Reverse Recovery Charge		-	10	-	nC

Note :

- 1、 The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3、 The EAS condition: $T_J=25^\circ\text{C}, V_{DD}=15V, V_G=4.5V, R_G=25\Omega, L=0.5mH, I_{AS}=21A$
- 4、 The power dissipation is limited by 175 $^\circ\text{C}$ junction temperature
- 5、 The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

Typical Characteristics

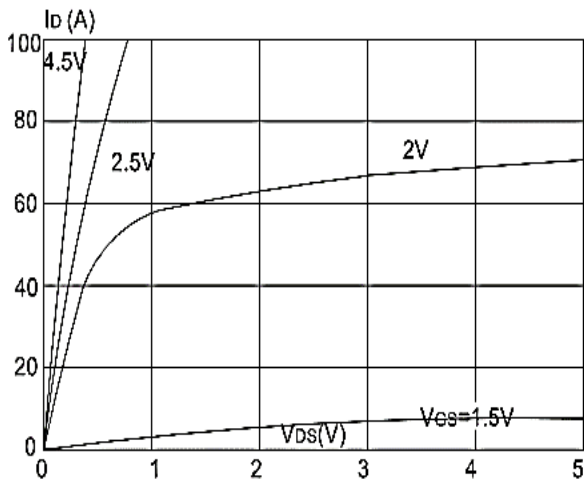


Figure 1: Output Characteristics

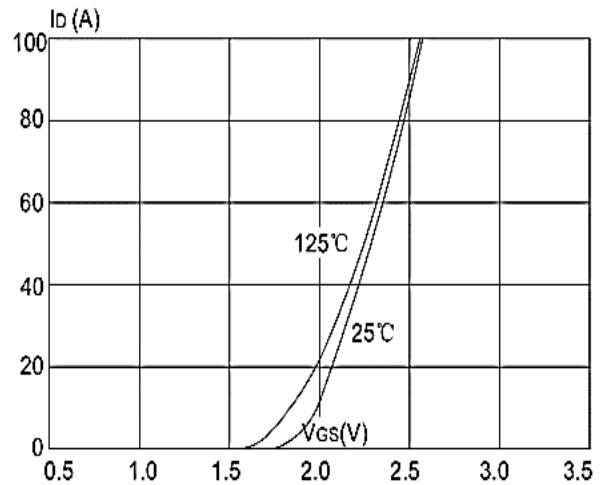


Figure 2: Typical Transfer Characteristics

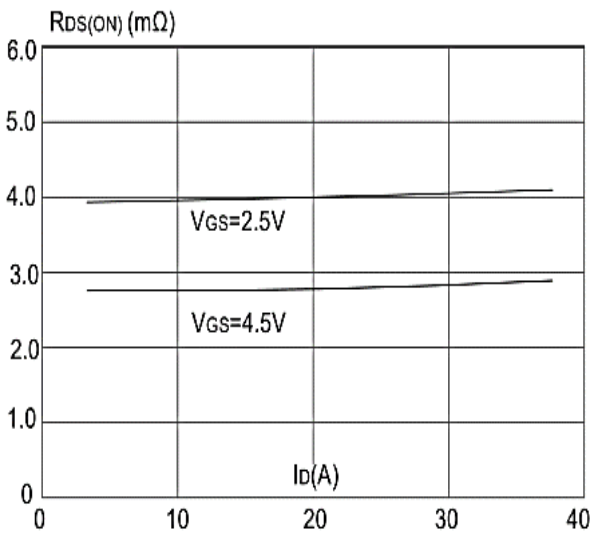


Figure 3: On-resistance vs. Drain Current

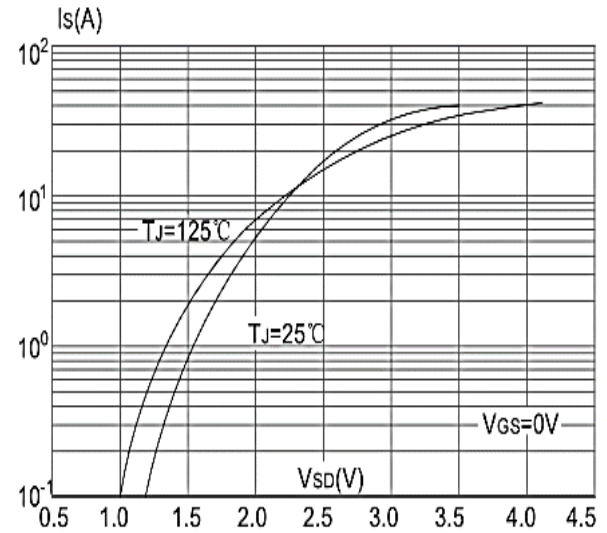
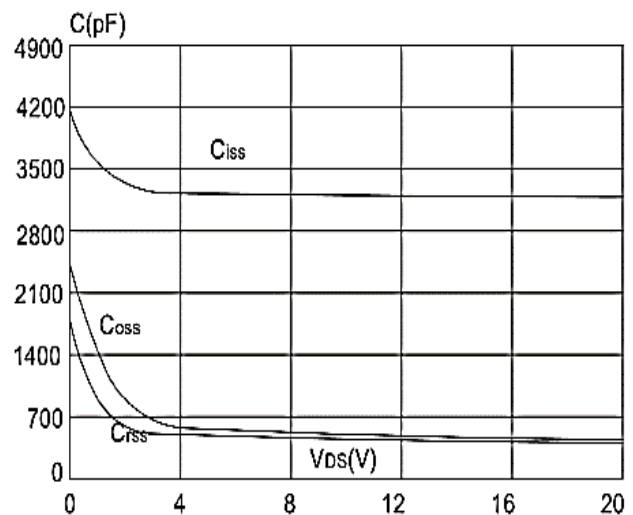
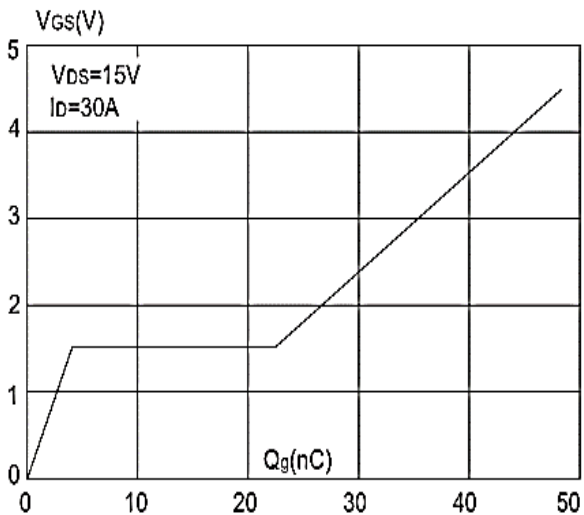


Figure 4: Body Diode Characteristics



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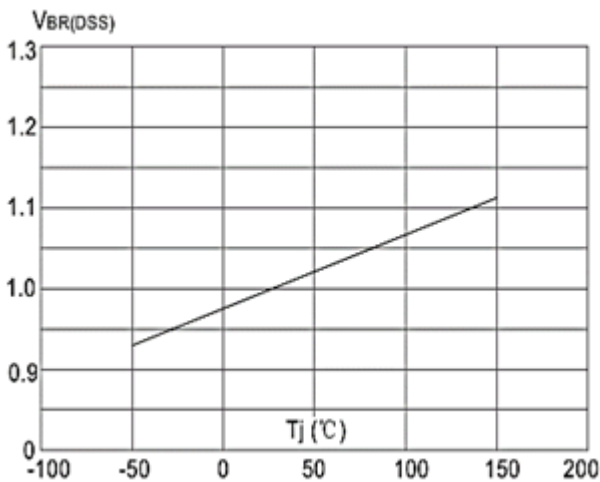


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

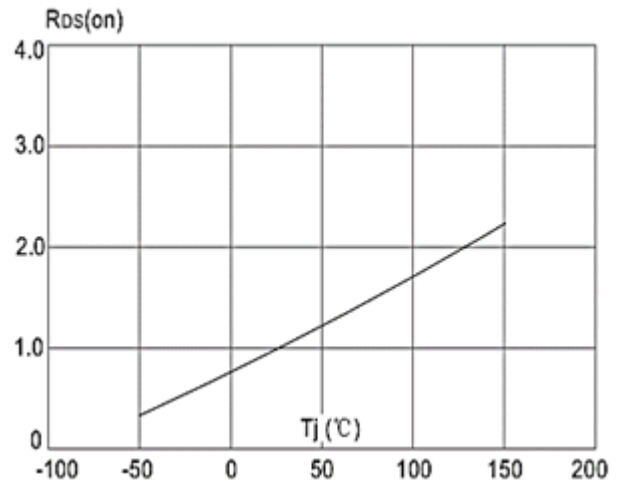


Figure 8: Normalized on Resistance vs. Junction Temperature

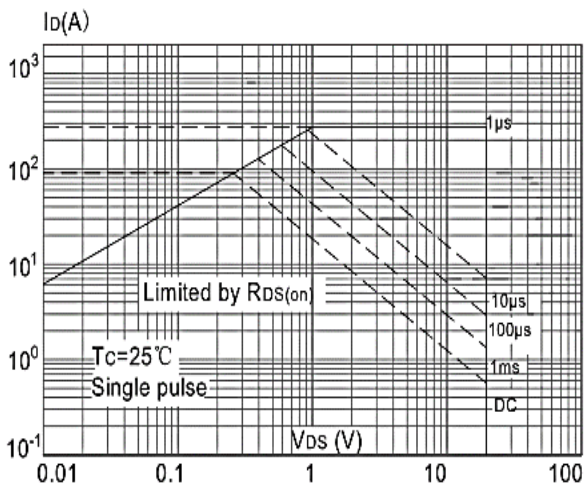


Figure 9: Maximum Safe Operating Area

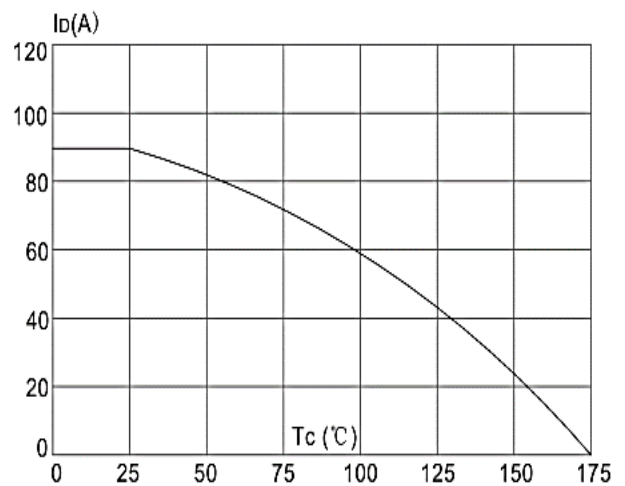


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

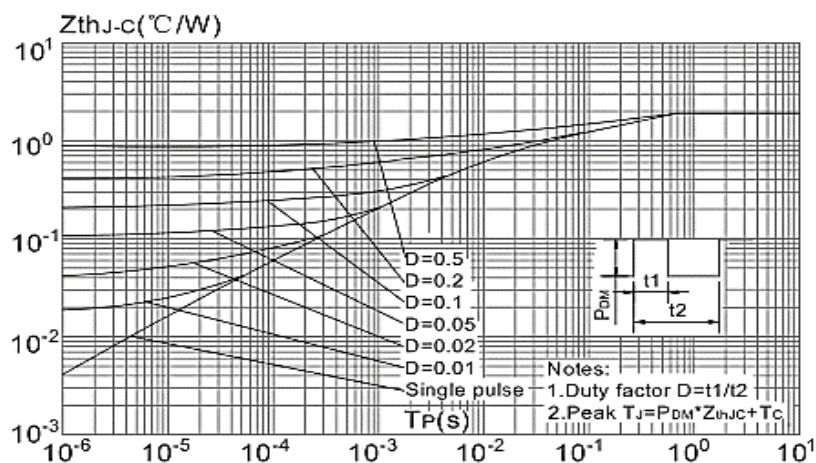
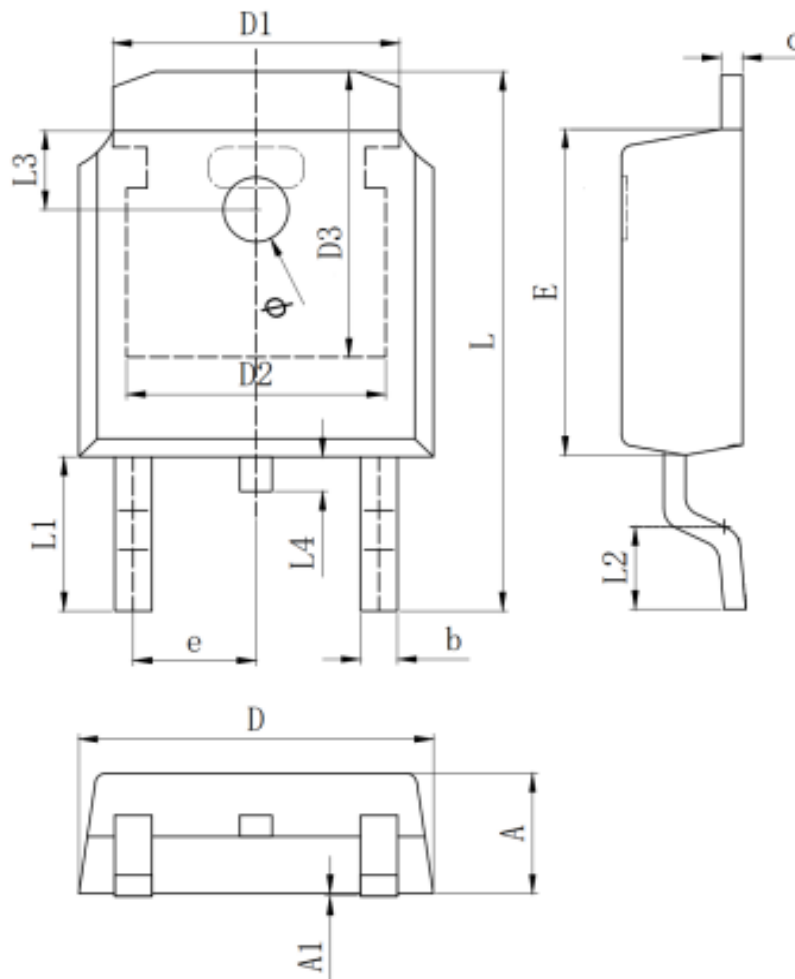


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambien

Package Mechanical Data: TO252-3L



Symbol	Dim in mm		
	min	tpy	max
A	2.1	2.3	2.5
A1	0	0.064	0.128
b	0.64	0.75	0.86
c	0.45	0.52	0.6
D	6.4	6.6	6.8
D1	5.33REF		
D2	4.83REF		
D3	5.25REF		
E	5.9	6.1	6.3
e	2.286TYP		
L	9.8	10.1	10.4
L1	2.888REF		
L2	1.4	1.5	1.7
L3	1.65REF		
L4	0.6	0.8	1
φ	1.1	1.2	1.3

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Edition	Date	Change
Rve1.0	2019/8/31	Initial release

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